

Abstract

A method of testing current sinking and sourcing capability of a driver in an IC calls for positioning a
5 charge storage element at an output of the driver and
charging it to a known voltage value. A pulse of known
duration and voltage level is applied to an input of the
driver and a resulting voltage value is measured at the
output of the driver. A current flow through the driver
10 is determined to be within testing limits by comparing an
expected voltage value against the resulting voltage
value.

An apparatus for testing current sinking and
sourcing capacity of a driver in an IC has the driver
15 with a charge storage element of known or measurable
capacitive value at an output of the driver. An input
circuit permits application of a test pulse of known
duration and data input values to the driver. A receiver
accepts an output of the driver for determining a
20 threshold voltage value at the driver output.